

## Tricaesium tetraselenidoarsenate(V) monohydrate

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### Key indicators

Single-crystal X-ray study  
 $T = 292\text{ K}$   
Mean  $\sigma(\text{Se}-\text{As}) = 0.004\text{ \AA}$   
H-atom completeness 0%  
 $R$  factor = 0.068  
 $wR$  factor = 0.201  
Data-to-parameter ratio = 27.7

For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.

The title compound,  $\text{Cs}_3\text{AsSe}_4 \cdot \text{H}_2\text{O}$ , contains discrete tetrahedral tetraselenidoarsenate(V) anions. The solvent water O atom participates in the coordination spheres of all three independent Cs cations, as do, in each case, seven Se atoms.

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### Comment

The discrete tetrahedral  $[\text{AsSe}_4]^{3-}$  anion has been characterized by X-ray structural analysis in  $[\text{Li}(\text{NH}_3)_4]_3\text{AsSe}_4$  (Korber & Grothe, 2001),  $\text{Na}_3\text{AsSe}_4 \cdot 9\text{H}_2\text{O}$  (Krebs *et al.*, 1990),  $\text{Rb}_3\text{AsSe}_4$  and  $\text{Cs}_3\text{AsSe}_4$  (Wachhold & Sheldrick, 1996),  $\text{Rb}_3\text{AsSe}_4 \cdot 2\text{Se}_6$  and  $\text{Cs}_3\text{AsSe}_4 \cdot 2\text{Cs}_2\text{As}_2\text{Se}_4 \cdot 6\text{Te}_4\text{Se}_2$  (Wachhold & Sheldrick, 1997), and  $\text{Ba}_2\text{AsSe}_4(\text{OH}) \cdot 2\text{H}_2\text{O}$  (Kaub, 1986). For instance, red crystals of  $M_3\text{AsSe}_4$  ( $M = \text{Rb}$  or  $\text{Cs}$ ) can be obtained by methanolothermal reaction of  $M_2\text{CO}_3$  with  $\text{As}_2\text{Se}_3$  and Se in appropriate molar ratio at 453 K.

We have now discovered that, on changing the solvent from methanol to an equimolar  $\text{H}_2\text{O}/\text{CH}_3\text{OH}$  mixture for  $M = \text{Cs}$ , the title monohydrate,  $\text{Cs}_3\text{AsSe}_4 \cdot \text{H}_2\text{O}$ , (I), is formed, rather than  $\text{Cs}_3\text{AsSe}_4$ .

The discrete tetraselenidoarsenate(V) anions of (I) exhibit As—Se distances between 2.308 (4) and 2.316 (4) Å (Fig. 1 and Table 1), which are similar to those in the range 2.306–2.336 Å found in  $\text{Rb}_3\text{AsSe}_4$  and  $\text{Cs}_3\text{AsSe}_4$ . As in these selenidoarsenates(V), seven Se atoms participate in the coordination spheres of each of the alkali metal cations, which are sited between the tetrahedral  $[\text{AsSe}_4]^{3-}$  anions (Fig. 2). Additional  $\text{Cs}\cdots\text{O}$  contacts of 3.09 (2) (Cs1), 3.54 (2) (Cs2) and 3.34 (2)/3.39 (2) Å (Cs3) lead to total coordination numbers of, respectively, 8, 8 and 9 for the  $\text{Cs}^+$  cations of (I).

### Experimental

$\text{As}_2\text{Se}_3$  (193.4 mg, 0.5 mmol), Se (79.0 mg, 1.0 mmol) and  $\text{Cs}_2\text{CO}_3$  (977.5 mg, 3.0 mmol) were heated to 393 K in an  $\text{H}_2\text{O}/\text{CH}_3\text{OH}$

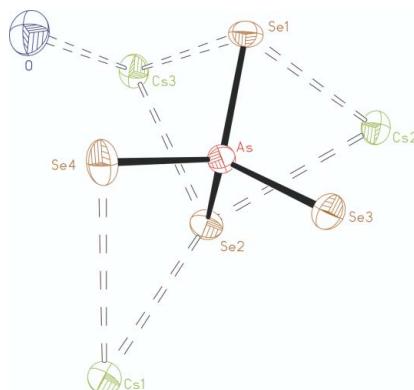


Figure 1

The asymmetric unit of (I). Displacement ellipsoids are drawn at the 50% probability level.

mixture (1:1 v/v, 0.8 ml) in a sealed glass tube. After 2 d, the contents were cooled to room temperature to afford red crystals of  $\text{Cs}_3\text{AsSe}_4\cdot\text{H}_2\text{O}$  in 32% yield.

#### Crystal data



$M_r = 807.51$

Monoclinic,  $P2_1/n$

$a = 9.994$  (3) Å

$b = 10.541$  (4) Å

$c = 12.372$  (6) Å

$\beta = 91.73$  (2)°

$V = 1302.8$  (9) Å<sup>3</sup>

$Z = 4$

$D_x = 4.117 \text{ Mg m}^{-3}$

Mo  $K\alpha$  radiation

Cell parameters from 18 reflections

$\theta = 5.5\text{--}12.7^\circ$

$\mu = 22.00 \text{ mm}^{-1}$

$T = 292$  (2) K

Block, red

$0.15 \times 0.13 \times 0.11 \text{ mm}$

#### Data collection

Siemens P4 four-circle diffractometer

$\omega$  scans

Absorption correction:  $\psi$ -scan (*XPREP* in *SHELXTL*; Sheldrick, 1995)

$T_{\min} = 0.054$ ,  $T_{\max} = 0.092$

2449 measured reflections

2295 independent reflections

1399 reflections with  $I > 2\sigma(I)$

$R_{\text{int}} = 0.046$

$\theta_{\text{max}} = 25.0^\circ$

$h = 0 \rightarrow 11$

$k = -12 \rightarrow 0$

$l = -14 \rightarrow 14$

3 standard reflections

every 97 reflections

intensity decay: 0.1%

#### Refinement

Refinement on  $F^2$

$R(F^2) > 2\sigma(F^2) = 0.068$

$wR(F^2) = 0.201$

$S = 1.15$

2295 reflections

83 parameters

H atoms not located

$w = 1/[\sigma^2(F_o^2) + (0.0949P)^2]$

where  $P = (F_o^2 + 2F_c^2)/3$

$(\Delta/\sigma)_{\text{max}} < 0.001$

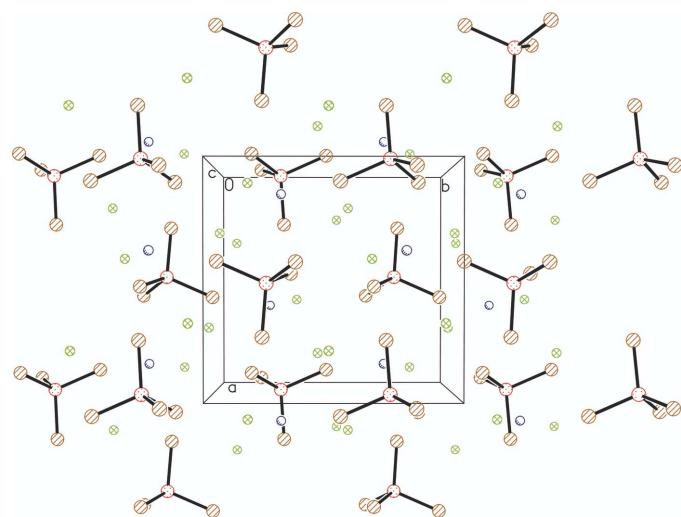
$\Delta\rho_{\text{max}} = 1.95 \text{ e } \text{\AA}^{-3}$

$\Delta\rho_{\text{min}} = -2.41 \text{ e } \text{\AA}^{-3}$

**Table 1**  
Selected geometric parameters (Å, °).

|                         |             |                        |             |
|-------------------------|-------------|------------------------|-------------|
| Cs1–O <sup>i</sup>      | 3.09 (2)    | Cs2–Se4 <sup>vii</sup> | 4.002 (4)   |
| Cs1–Se1 <sup>ii</sup>   | 3.533 (3)   | Cs3–O                  | 3.34 (2)    |
| Cs1–Se2                 | 3.620 (3)   | Cs3–O <sup>ix</sup>    | 3.39 (2)    |
| Cs1–Se3 <sup>iii</sup>  | 3.743 (3)   | Cs3–Se1 <sup>vi</sup>  | 3.635 (3)   |
| Cs1–Se4 <sup>iv</sup>   | 3.756 (4)   | Cs3–Se2                | 3.717 (3)   |
| Cs1–Se2 <sup>v</sup>    | 3.928 (4)   | Cs3–Se3 <sup>vi</sup>  | 3.718 (3)   |
| Cs1–Se3 <sup>vi</sup>   | 4.024 (4)   | Cs3–Se1                | 3.737 (3)   |
| Cs1–Se4                 | 4.024 (4)   | Cs3–Se4 <sup>ix</sup>  | 3.933 (4)   |
| Cs2–O <sup>vi</sup>     | 3.54 (2)    | Cs3–Se2 <sup>ix</sup>  | 4.079 (3)   |
| Cs2–Se4 <sup>vii</sup>  | 3.588 (3)   | Cs3–Se3 <sup>x</sup>   | 4.130 (4)   |
| Cs2–Se1 <sup>vi</sup>   | 3.650 (3)   | As–Se4                 | 2.308 (4)   |
| Cs2–Se1                 | 3.668 (3)   | As–Se2                 | 2.313 (4)   |
| Cs2–Se2 <sup>viii</sup> | 3.729 (3)   | As–Se3                 | 2.316 (3)   |
| Cs2–Se2                 | 3.822 (3)   | As–Se1                 | 2.316 (4)   |
| Cs2–Se3 <sup>viii</sup> | 3.929 (4)   |                        |             |
| Se4–As–Se2              | 109.08 (14) | Se4–As–Se1             | 108.04 (14) |
| Se4–As–Se3              | 110.24 (15) | Se2–As–Se1             | 109.26 (14) |
| Se2–As–Se3              | 110.12 (14) | Se3–As–Se1             | 110.07 (13) |

Symmetry codes: (i)  $x + \frac{1}{2}, -y + \frac{3}{2}, z + \frac{1}{2}$ ; (ii)  $x + 1, y, z$ ; (iii)  $x + \frac{1}{2}, -y + \frac{3}{2}, z - \frac{1}{2}$ ; (iv)  $-x + \frac{3}{2}, y + \frac{1}{2}, -z + \frac{1}{2}$ ; (v)  $-x + \frac{3}{2}, y - \frac{1}{2}, -z + \frac{1}{2}$ ; (vi)  $-x + \frac{1}{2}, y + \frac{1}{2}, -z + \frac{1}{2}$ ; (vii)  $x - \frac{1}{2}, -y + \frac{3}{2}, z + \frac{1}{2}$ ; (viii)  $-x + 1, -y + 2, -z + 1$ ; (ix)  $-x + 1, -y + 2, -z$ ; (x)  $x - \frac{1}{2}, -y + \frac{3}{2}, z - \frac{1}{2}$ .



**Figure 2**

A projection of the structure of (I), perpendicular to the  $ab$  plane. Atom colour codes: Cs green cross-hatched circles, Se orange hatched circles, As red dotted circles, O blue semi-hatched circles.

The water H atoms could not be located in a final difference synthesis and were not, therefore, included in the refinement. The highest peak in the final difference Fourier synthesis is 2.30 Å from Cs3 and the deepest hole is 0.96 Å from the same atom.

Data collection: *R3m/V* (Siemens, 1989); cell refinement: *R3m/V*; data reduction: *XDISK* (Siemens, 1989); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Sheldrick, 1995); software used to prepare material for publication: *SHELXL97*.

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